CORRELATION UPDATE

DAC IBIS SUMMIT, ANAHEIM CA
JUNE 15, 2010

ANDERS EKHOLM, ERICSSON & MIKE LABONTE, CISCO SYSTEMS

IBIS QUALITY TASK GROUP

- **Web:**
  - http://www.vhdl.org/pub/ibis/quality_wip
- **Email list:**
  - http://www.freelists.org/list/ibis-quality
  - Or send email
    - To: ibis-quality-request@freelists.org
    - Subject: subscribe
- **Meetings:**
  - Every second Tuesday from 11:00am to 12:00pm Eastern Time
- **Questions? Mike LaBonte milabont@cisco.com**

NEW ACTIVITIES 2010

Correlation issues discussed

- Where to go from here
- Accuracy handbook
- Correlation handbook

What kinds of correlation

- Overlay & Envelope Metric
- Feature Selective Validation , Metric-correlation
- Feature Selective Validation , IEEE-P1597.2 D6.5

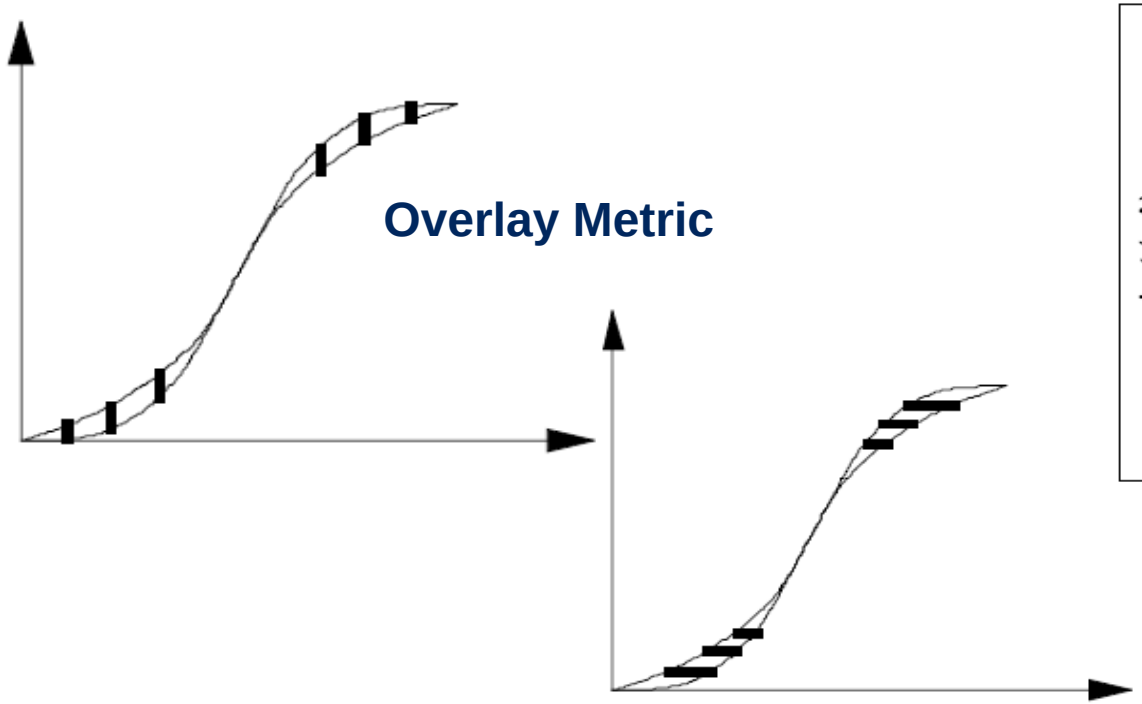
CORRELATION

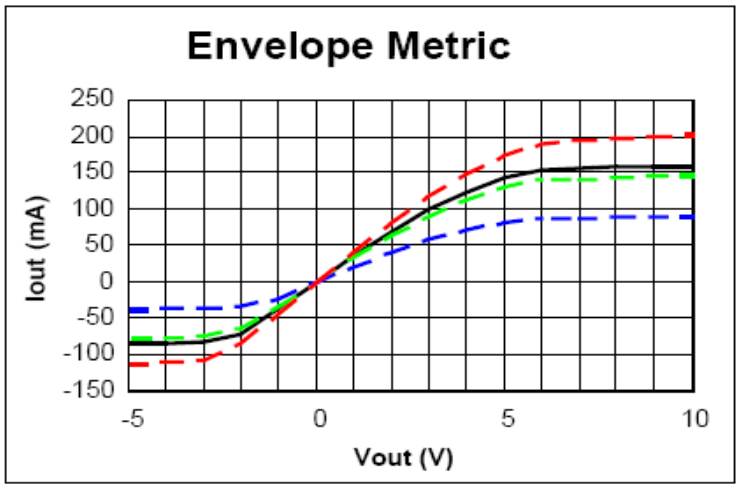
›Overlay & Envelope Metric

Test data is supposed to be between worst and best corners data

Accuracy Handbook - Greg Edlund for Overlay and Envelope Metric:

http://www.eda.org/ibis/accuracy/handbook.pdf





CORRELATION

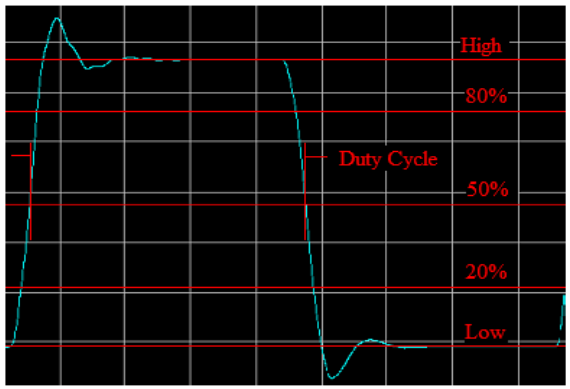
› FSV Feature Selective Validation, Metric-correlation

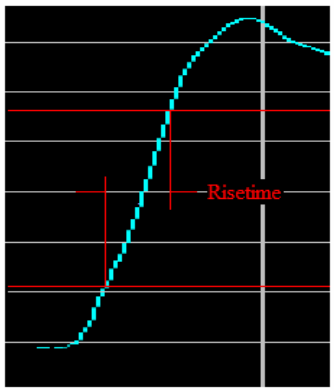
Correlate a specified number of features such as amplitude, edge-rate, duty-cycle, etc..

Reference or copy a summary slide from the David Banas presentation:

http://www.eda.org/ibis/summits/jun07/banas.pdf

– high level, low level, rise time, fall time, and duty cycle





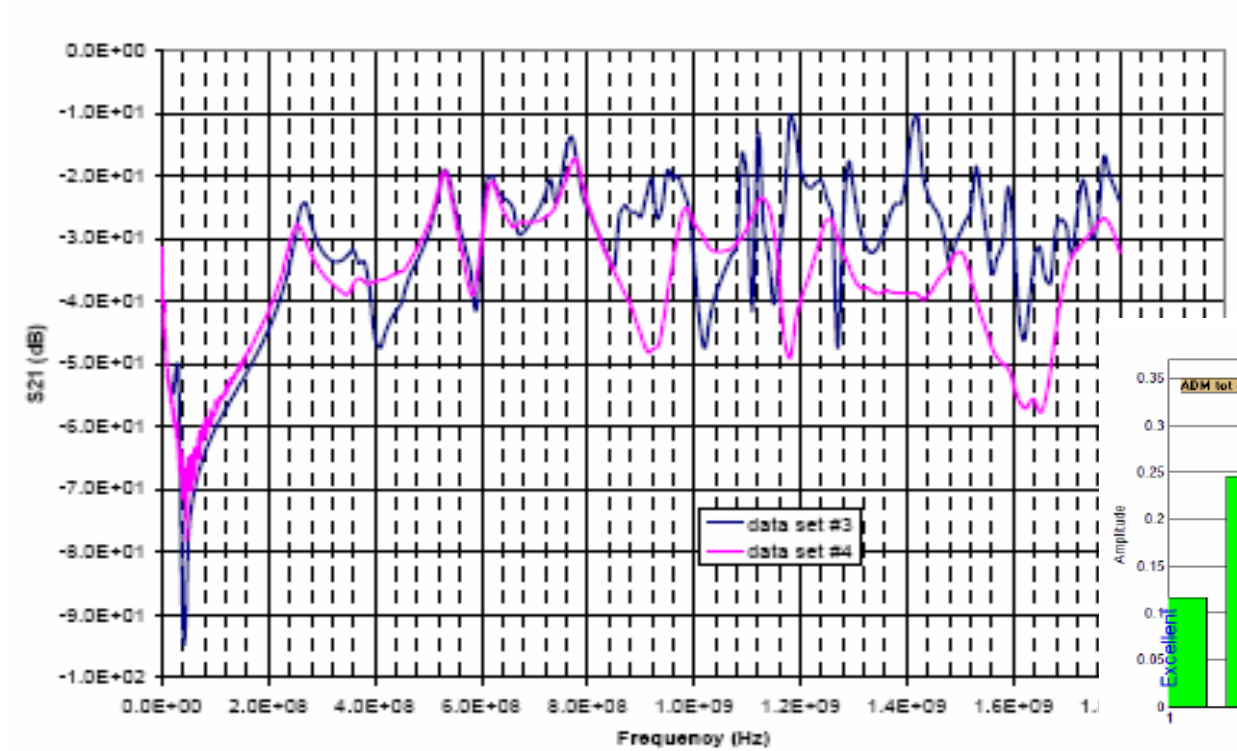
CORRELATION

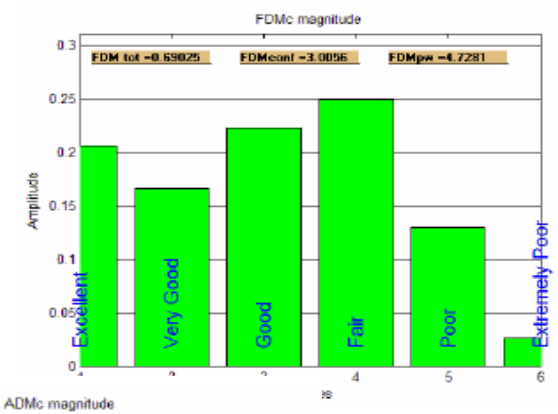
› FSV Feature Selective Validation, IEEE-P1597.2 D6.5

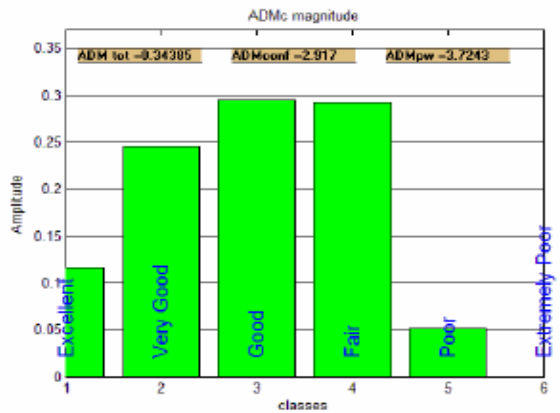
FTT test data and golden data, compare low frequency and high frequency part.

IEEE Draft standard:

http://www.eda.org/pub/ibis/quality_wip/archive-date.html







IEEE EMC Symposium 2008, Proper Model Validation is Important for all EMI/EMC Applications, Bruce Archambeault, Samuel Connor

REGULAR 2009/2010 IQ MEETING PARTICIPANTS

- Cisco Systems
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- IO Methodology
- Micron Technology
- Nokia Siemens Networks
- Texas Instruments
- Teraspeed Consulting Group

ERICSSON